

Notice of References Cited	Application/Control No. 09/609,714	Applicant(s)/Patent Under Reexamination HACK ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	U	Is your supply chain playing by the rules? Perry A Trunick. Transportation & Distribution. Cleveland:Sep 1998. Vol. 39, Iss. 9, p. 51-55 (4 pp.)
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	W	SCM: Another acronym to help broaden enterprise management Lawrence S Gould. Automotive Manufacturing & Production. Cincinnati:Mar 1998. Vol. 110, Iss. 3, p. 64-69 (6 pp.)
	X	Putting an end to islands of manufacturers Anonymous. Modern Materials Handling. Boston:Feb 1998. Vol. 53, Iss. 2, p. 40-41 (2 pp.)

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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	X	SAP and Microsoft Work Together to Establish Common Business Frameworks for Electronic-Commerce Content Business Editors, High-Tech Writers. BusinessWire. New York; Mar 4, 1998. pg1. ProQuest Document ID 39464102

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